Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/724,325	CRUZ ET AL.
Examiner	Art Unit
Paul D. Kim	3729

	SEARCHED		
Class	Subclass	Date	Examiner
29	592.1 825 827 831 832 846	4/11/2006	PK
174	52.4		
257	678 684	/	
438	118	₩ .	
		-	
		-	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	ext Search achment	6/28/2006	PK

	CH NOTES EARCH STRATEGY)
	DATE	EXMR
Consulted Sara Crane (257) No Search	4/11/2006	PK
Scott Geyer (438)	4/11/2006	PK
Carl Arbes (29)	4/12/2006	PK
Text Search EAST/NPL (IEEE)	4/12/2006	PK
Updated Text Search EAST/PGPub	6/28/2006	PK